

Notice of References Cited	Application/Control No. 10/621,843		Applicant(s)/Patent Under Reexamination MATSUSHITA, SHINJI	
	Examiner Chriss S. Yoder, III		Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0149689 A1	10-2002	Sannoh et al.	348/333.02
*	B	US-5,331,419 A	07-1994	Yamada et al.	348/64
*	C	US-5,689,742	11-1997	Chamberlain, IV, Frederick Rockwell	396/313
*	D	US-5,650,607 A	07-1997	Kusaka, Yosuke	250/201.8
*	E	US-2003/0067551 A1	04-2003	Venturino et al.	348/364
*	F	US-2001/0040629	11-2001	Miyagi et al.	348/232
*	G	US-7,173,660 B2	02-2007	Toji et al.	348/333.02
*	H	US-2002/0008765	01-2002	Ejima et al.	348/239
*	I	US-6,888,567 B2	05-2005	Watanabe, Sayuri	348/211.8
*	J	US-3,812,288	05-1974	Walsh et al.	378/98.6
*	K	US-4,453,814	06-1984	Satoh et al.	396/318
*	L	US-5,557,358	09-1996	Mukai et al.	396/296
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.